

Docket No.: 60188-725

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
	:	
Mitsuyasu OHTA, et al.	:	Confirmation Number:
	:	
Serial No.: Continuation of Appl. No. 09/381,377	:	Group Art Unit:
	:	
Filed: January 06, 2004	:	Examiner:
	:	
For:		FUNCTIONAL BLOCK FOR INTEGRATED CIRCUIT, SEMICONDUCTOR INTEGRATED CIRCUIT, METHOD FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUIT, AND METHOD FOR DESIGNING SEMICONDUCTOR INTEGRATED CIRCUIT

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Patent Application  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

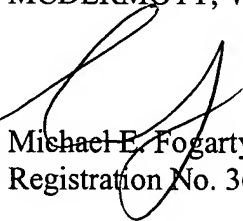
**Serial No.:** Continuation of Appl. No.

The references were cited by or submitted to the U.S. Patent and Trademark Office in parent application Serial No. 09/381,377, filed September 20, 1999, which is relied upon for an earlier filing date under 35 USC 120. Thus, copies of these references are not attached. 37 CFR 1.98(d).

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY



Michael E. Fogarty  
Registration No. 36,139

600 13<sup>th</sup> Street, N.W.  
Washington, DC 20005-3096  
(202) 756-8000 MEF:prg  
Facsimile: (202) 756-8087  
**Date: January 6, 2004**

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>				ATTY. DOCKET NO. <b>60188-725</b>		SERIAL NO. <b>Continuation of Appl. N . 09/381,377</b>	
<b>(PTO-1449)</b>				APPLICANT <b>Mitsuyasu OHTA, et al.</b>			
				FILING DATE <b>January 06, 2004</b>		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US 5,930,271	07/27/1999	Takahashi			
		US 5,386,423	01/31/1995	Koo et al.			
		US 5,809,039	09/15/1998	Takahashi et al.			
		US 6,055,661	04/25/2000	Luk			
		US 6,119,257	09/12/2000	Negishi			
		US 6,108,806	08/22/2000	Abramovici et al.			
		US 5,790,561	08/4/1998	Borden et al.			
		US 5,805,608	09/8/1998	Baeg et al.			
		US 5,812,562	09/22/1998	Baeg			
		US					
		US					
		US					
		US					
		US					
		US					
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number 4 -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 62-62275	18/03/87				
		JP 1-237472	21/09/89				
		JP 6-186302	08/07/94				
		JP 5-52910	02/03/93				
		JP 5-158724	25/06/93				
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		Y. ZORIAN, "Test Requirements for Embedded Core-Based Systems and IEEE P1500", International Test Conference Proceedings, 11/01/1997 – 11/06/1997, pages 191-199.					
		M. ABRAMOVICI, "Design For Testability Techniques: A Comparative Analysis", June 2002, USPTO Lecture.					
EXAMINER				DATE CONSIDERED			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.